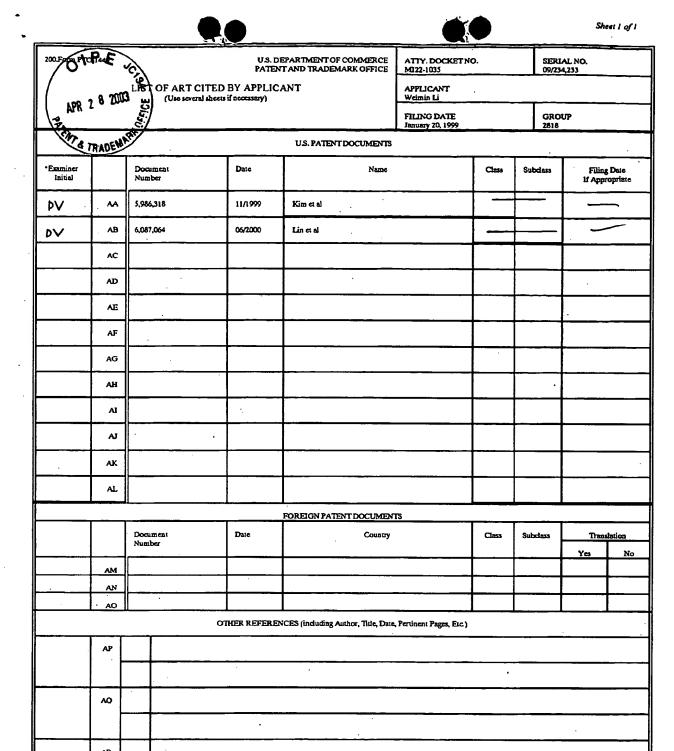
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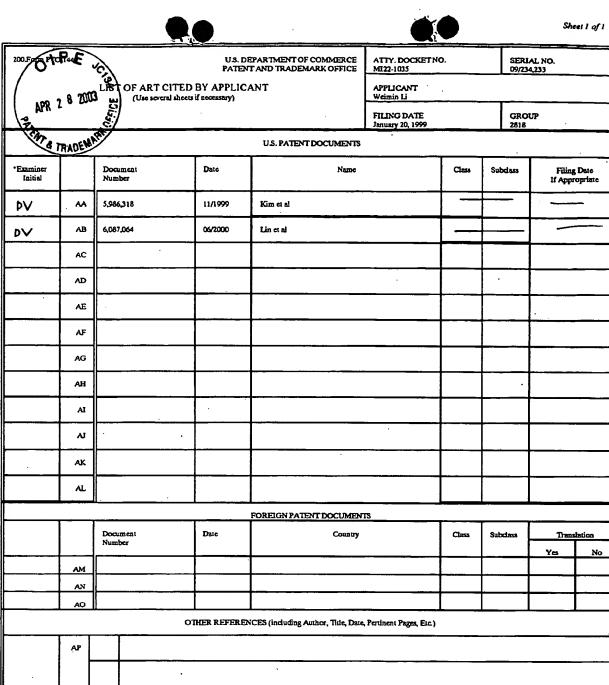
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DV		Chemistry, Vol. 95, No. 11, 1991; pp. 4393-4400
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		AB	5,67	7,015	10/1994	Hasegawa						
		AC	5,783	3,493	7/1998	Yeh et al				!		
		AD	5,80	7,660	9/1998	Lin et al				!	_	
		ΑE	4,83	3,096	5/1989	Huang et al		_	<del></del>	-		
		AF	5,40	5,489	4/1995	Kim et al				: -	_	
		AG	5,476	0,772	11/1995	Woo .	·				]	
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	-	AJ	4,80	5,683	2/1989	Magdo et al		_				
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		AB	4,600,671	7/1986	Saitoh et al					_	
		AC	5,753,320	5/1998	Mikoshiba et al						
		AD	5,356,515	10/1994	Tahara et al						
		AE	5,674,356	10/07/97	Nagayama					_	
		AF	5,731,242	03/24/98	Parat et al.						
		AG	5,741,721	04/21/98	Stevens						
		АН	5,034,348	07/23/91	Hartswick et al.						
		AI	5,472,829	12/05/95	Ogawa				-		
		ĄJ	5,641,607	06/24/97	Ogawa et al.	·					
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. 1	N	АО	D.R. McKenzie et	al., "New Techn	nology for PACVD1°, Surface an	nd Coatings Technolog	gy. 82 (199	6), pp. 326	-333.		
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1	) /	АР	S. McClatchie et al.;	; "Low Dielectric	Constant Flowfill® Technology Fo	or IMD Applications"; 1	undated; 7 pa	ages			
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ŗ	V	AQ	K. Beekmann et al	.; "Sub-micron (	Gap Fill and In-Situ Planarisation	n using Flowfill™ Tec	hnology*: C	october 199	5; pp. 1-7		
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Form PTO-144 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE ATTY. DOCKET NO. MI22-1035 SERIAL NO. 09/234,233 AUS 0 3 2001 LIST OF ART CITED BY APPLICANT
(Use see al sheets if necessary) APPLICANT al sheets if necessary) FILING DATE January 20, 1999 GROUP 2818 **U.S. PATENT DOCUMENTS** \*Examiner Document Date Name Class Subclass Filing Date Initial Number If Appropriate DV 5,670,297 09/23/97 Ogawa et al. AB 5,677,111 10/14/97 Ogawa AC 5,698.352 12/16/97 Ogawa et al. AD 5,831,321 11/03/98 Nagayama ΑE 5,591,566 01/07/97 Ogawa AF 6,008,124 12/28/99 Sekiguchi et al. AG 5,340,621 08/23/94 Matsumoto et al. AH 5,600,165 02/04/97 Tsukamoto et al. ΑI 5,872,385 02/16/99 Taft et al. ΑJ 5,960,289 09/28/99 Tsui et al. AK 5,968,324 10/19/99 Cheung et al. AL 6,020,243 02/01/00 Wallace et al. FOREIGN PATENT DOCUMENTS Document Number Date Country Class Subclass Translation Yes No DV ΑM 0 588 087 A2 8/18/93 EPO DV 0 588 087 A3 AN 8/18/93 EPO OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) ΑO A. Kiermasz et al.; "Planarisation for Sub-Micron Devices Utilising a New Chemistry"; Electrotech, February 1995; 2 pages DV ΑP IBM Technical Disclosure Bullatin \*Low-Temperature Deposition of SiO2, Si3N4 or SiO2-Si3N4," Vol. 28, No. 9, p. 4170, Feb. 1986. DV AQ ARTICLE: Bencher, C. et al., "Dielectric antireflective coatings for DUV lithography", Solid State Technology (March 1997), pp.109-114. DV grular id **EXAMINER** DATE CONSIDERED 10/11/01 \*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.

Include copy of this form with next communication to applicant.

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	AB	5,948,482	09/07/99	Brinker et al.			-		
	AC	5,800,877	09/01/98	Maeda et al.					_
	ΑD	5,260,600	11/09/93	Harada				7	
	AE	4,992,306	02/12/91	Hochberg et al.					
	AF	4,702,936	10/27/87	Macda et al.			-	)	
	AG	4,863,755	09/05/89	Hess et al.		-	_		
	AH	5,234,869	08/10/93	Mikata et al.			-		
	Al	5,302,366	04/12/94	Schuette et al.			٠,	-	
	Ą	5,591,494	01/07/97	Sato et al.			<u> </u>	_	
	AK	5,968,611	10/19/99	Kaloyeros et al.			_		
	AL	6,159,871	12/12/00	Loboda et al.			_		
	АМ	5,744,399	4/1998	Rostoker					
,	AN	5,883,014	3/1999	Chen			-		_
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DV	AS	Julius Grant, Hackt	's Chemical Dict	ionary, Fourth Edition, McGraw-F	iill Book Company, ©	1969, rented by	Grant © 19	72, pp. 27	
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	AB	6,156	1,674	12/5/00	Lietal				<u> </u>		
	AC	6,461	.,003	10/24/95	Haveman	1					
	AD	6,12	14,641	9/26/00	Matsura						
	AE	5,554	1,567	9/10/96	Wang					<u> </u>	
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DV	AK		Ralis, Kenneth M.,	Introduction to	Materials Sc	cience and Engineering	g", John Wiley & Sons,	O 1976, pp.	312-313	:	
ρV	AL		Ravi K. Lax,an, "Syr	nthesizing Low-k	CVD Mater	rials for Fab Use", Ser	niconductor Internation	nal, Nov. 200	O, 10 pps.		
ρV	АМ		Anonymous, "New g	as helps make fa	ster IC's, M	achine Design Clevela	nd, O Penton Media, I	nc., Novemb	er 4, 1999,	. pp. 118	
- DV	AN						nd Versatility in PECVE chemical Society, Abstr				m on
DV	АО		ARTICLE: Benche	r, C. et al.,"Diele	ctric antiref	flective coatings for D	UV lithography", Solid	State Techno	ology (Ma	rch 1997),	
			pp. 109-114.								
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•			Vol. 3049 (1997), pp	. 963-973.				• •			
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	AB	6,096,656	08/2000	Matzka et aj			_			
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